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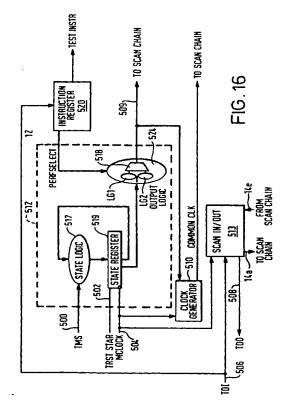
## **EUROPEAN PATENT APPLICATION**

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- (71) Applicant: SGS-THOMSON MICROELECTRONICS LTD. Bristol BS12 4SQ (GB)

- (51) Int CI.6: **G01R 31/3173**, G01R 31/3185, G06F 11/24, G06F 11/267
- (72) Inventor: Warren, Robert Bristol, Avon (GB)
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## (54) A controller for implementing scan testing

(57) A test access port controller is provided for implementing scan testing with a chain of scan latches on an integrated circuit. The test access port controller can implement a structural test or a performance test. Selection between the two types of test is achieved through logic circuitry of the test access port controller. An integrated circuit and a test system are also provided.



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## **EUROPEAN SEARCH REPORT**

Application Number EP 95 30 5859

	DOCUMENTS CONSIDERED TO BE RELEVANT				
Category	Citation of document with of relevant p	adication, where appropriate,	Relevant to claim	CLASSIFICATION OF THE APPLICATION (IBLCL6)	
X	PROCEEDINGS OF THE IEEE 1992 CUSTOM INTEGRATED CIRCUITS CONFERENCE, 3 May 1992, BOSTON, MA, USA pages 13.2.1 - 13.2.4, XP000340902 H. CHANG ET AL. 'Delay Test Techniques for Boundary Scan based Architectures' * page 13.2.1 - page 13.2.3, right column, line 26; figures 1-9 *		i	G01R31/3173 G01R31/3185 G06F11/24 G06F11/267	
A	JOURNAL OF ELECTRONIC TESTING: THEORY AND APPLICATIONS, vol.2, no.1, March 1991, DORDRECHT, NL pages 27 - 42, XP000214732 C.M. MAUNDER E AL. 'An Introduction to the Boundary Scan Standard: ANSI/IEEE Std 1149.1' * the whole document *				
A	EP-A-O 402 134 (TEXAS INSTRUMENTS INCORPORATED)  * the whole document *  * column 35, line 2 - line 15; figure 21 *  EP-A-O 548 585 (INTERNATIONAL BUSINESS MACHINES CORPORATION)  * the whole document *		1-8 9 9	TECHNICAL FIELDS SEARCHED (Int.Cl.6) GO6F	
x					
<b>A</b>	AT&T TECHNICAL JOURNAL, vol.73, no.2, March 1994, NEW YORK, USA pages 30 - 39, XP000445588 V.D. AGRAWAL ET AL. 'Built-In Self-Test for Digital Integrated Circuits' * page 34, right column, line 9 - page 35, left column, line 24; figures 1,2 *		9	·	
	The presont search report has b	een drawn up for all claims	1		
Place of search Date of completion of the search				Econolog	
THE HAGUE		19 January 1996	5 Abs	salom, R	
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